

N-Channel Enhancement Mode Power MOSFET

Description

The HM4110T uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of other applications.

General Features

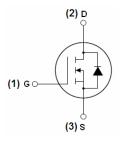
- $V_{DSS} = 100V, I_D = 210A$ $R_{DS(ON)} < 4.0 mΩ @ V_{GS} = 10V$ (Typ: 3.1 mΩ)
- Good stability and uniformity with high E_{AS}
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation

Application

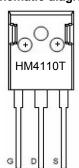
- DC motor drive
- High efficiency synchronous rectification in SMPS
- Uninterruptible power supply
- High speed power switching
- Hard switched and high frequency circuits

100% UIS TESTED!

100% ΔVds TESTED!



Schematic diagram



Marking and pin assignment



TO-247 top view

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM4110T	HM4110T	TO-247	-	-	-

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DSS}	100	V
Gate-Source Voltage	V _G s	±20	V
Drain Current-Continuous	I _D	210	А
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	140	А
Pulsed Drain Current	I _{DM}	850	А
Maximum Power Dissipation	P _D	385	W
Derating factor		2.57	W/°C
Single pulse avalanche energy (Note 3)	E _{AS}	2300	mJ
Peak Diode Recovery dv/dt (Note 4)	dv/dt	13	V/ns



Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 175	$^{\circ}\mathbb{C}$
Thermal Characteristic			
Thermal Pacistance Junction to Case (Note 1)	Paus	0.30	°C /\/

Electrical Characteristics (T_C=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	100	110	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =100V,V _{GS} =0V	-	-	1	μΑ
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±200	nA
On Characteristics						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS},I_{D}=250\mu A$	2	3	4	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =40A	-	3.1	4.0	mΩ
Forward Transconductance	g FS	V _{DS} =25V,I _D =40A	300	-	-	S
Dynamic Characteristics			-			l.
Input Capacitance	C _{lss}	V 05VVV 0V	-	16500	-	PF
Output Capacitance	C _{oss}	V_{DS} =25V, V_{GS} =0V, F=1.0MHz	-	1061	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.UIVIHZ	-	811	-	PF
Switching Characteristics			•			•
Turn-on Delay Time	t _{d(on)}	\/ 00\/ L 0A	-	68	-	nS
Turn-on Rise Time	t _r	V_{DD} =30V, I_{D} =2A V_{GS} =10V, R_{GEN} =2.5 Ω	-	45	-	nS
Turn-Off Delay Time	t _{d(off)}	VGS=10V,RGEN=2.312 (Note2)	-	215	-	nS
Turn-Off Fall Time	t _f		-	56	-	nS
Total Gate Charge	Qg	\/ -20\/ -20 \	-	377	-	nC
Gate-Source Charge	Q _{gs}	V_{DS} =30V, I_{D} =30A, V_{GS} =10V ^(Note2)	-	79	-	nC
Gate-Drain Charge	Q _{gd}	VGS-10V	-	118	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage	V _{SD}	V _{GS} =0V,I _S =40A	-	-	1.2	V
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF = 75A	-	69	-	nS
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note2)}$	-	108	-	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				(LS+LD)

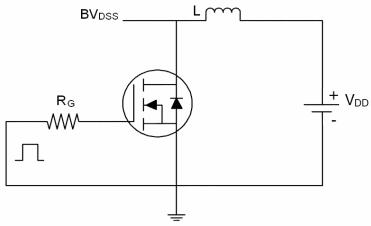
Notes:

- 1. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 2. Pulse Test: Pulse Width ≤ 400µs, Duty Cycle ≤ 2%.
- 3. EAS condition: Tj=25 $^{\circ}\text{C}$,VDD=37.5V,VG=10V,L=2mH,Rg=25 Ω ,IAS=37A
- 4. Isd \leqslant 125A, di/dt \leqslant 260A/ μ s, Vdd \leqslant V(BR)dss, TJ \leqslant 175°C

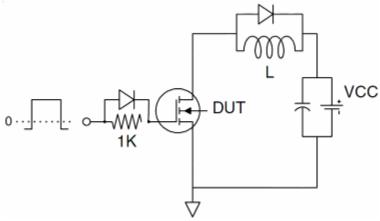


Test circuit

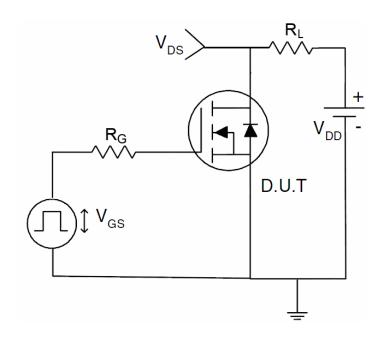
1) E_{AS} test Circuits



2) Gate charge test Circuit:



3) Switch Time Test Circuit:





Typical Electrical and Thermal Characteristics

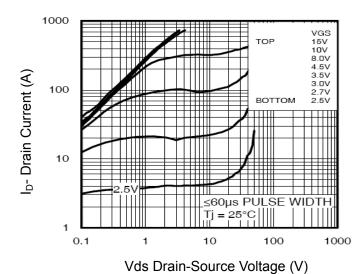
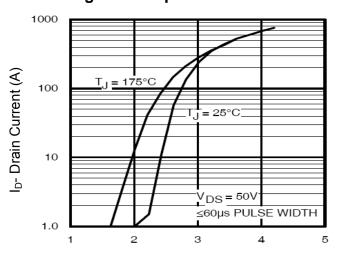


Figure 1 Output Characteristics



Vgs Gate-Source Voltage (V)

Figure 2 Transfer Characteristics

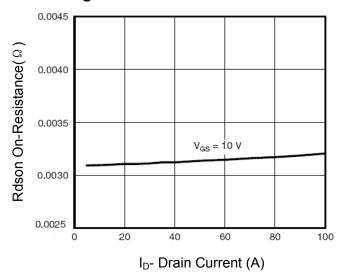
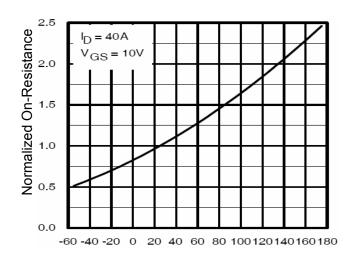


Figure 3 Rdson- Drain Current



T_J-Junction Temperature(°C)

Figure 4 Rdson-JunctionTemperature

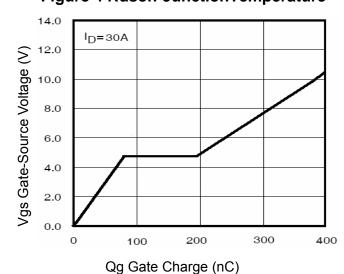
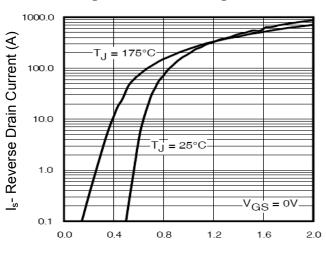


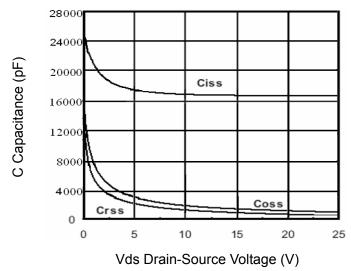
Figure 5 Gate Charge



Vsd Source-Drain Voltage (V)

Figure 6 Source- Drain Diode Forward





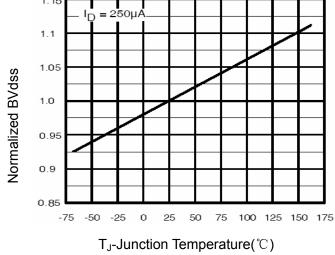
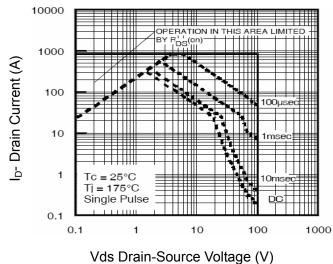


Figure 7 Capacitance vs Vds





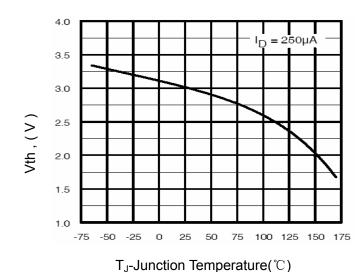


Figure 8 Safe Operation Area

Figure 10 V_{GS(th)} vs Junction Temperature

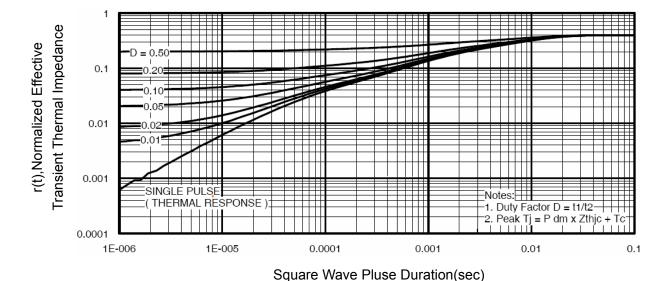
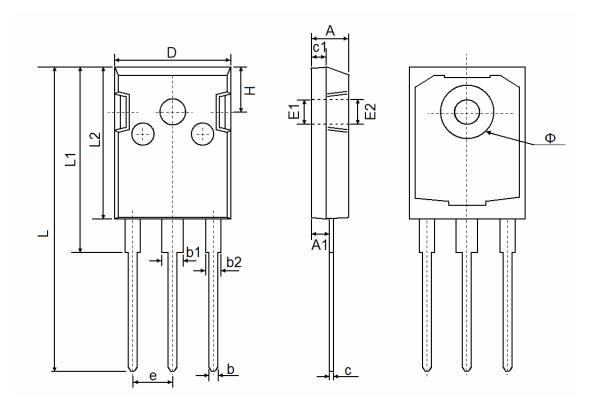


Figure 11 Normalized Maximum Transient Thermal Impedance



TO-247 Package Information



Combal	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
А	4.850	5.150	0.191	0.200	
A1	2.200	2.600	0.087	0.102	
b	1.000	1.400	0.039	0.055	
b1	2.800	3.200	0.110	0.126	
b2	1.800	2.200	0.071	0.087	
С	0.500	0.700	0.020	0.028	
c1	1.900	2.100	0.075	0.083	
D	15.450	15.750	0.608	0.620	
E1	3.50	00 REF	0.138 REF		
E2	3.60			2 REF	
L	40.900	41.300	1.610	1.626	
L1	24.800	25.100	0.976	0.988	
L2	20.300	20.600	0.799	0.811	
Ф	7.100	7.300	0.280	0.287	
е	5.45	5.450 TYP 0.215 TYP		TYP	
Н	5.980 REF		0.235 REF		



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